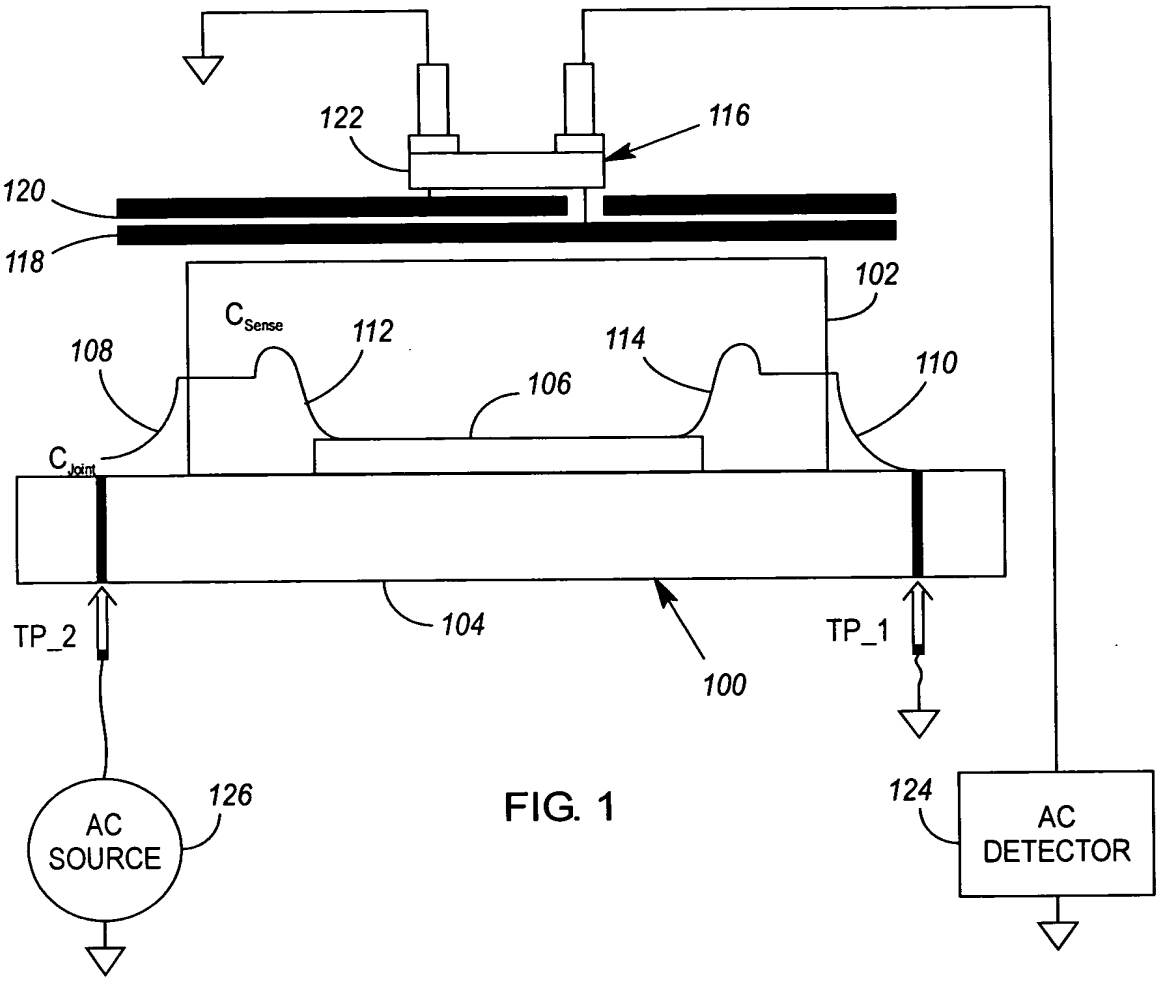
122
116
120
118
102
C_{Sense}
112
114
108
106
110
C_{Joint}
104
100
TP_2
TP_1
AC SOURCE
126
124
AC DETECTOR

FIG. 1

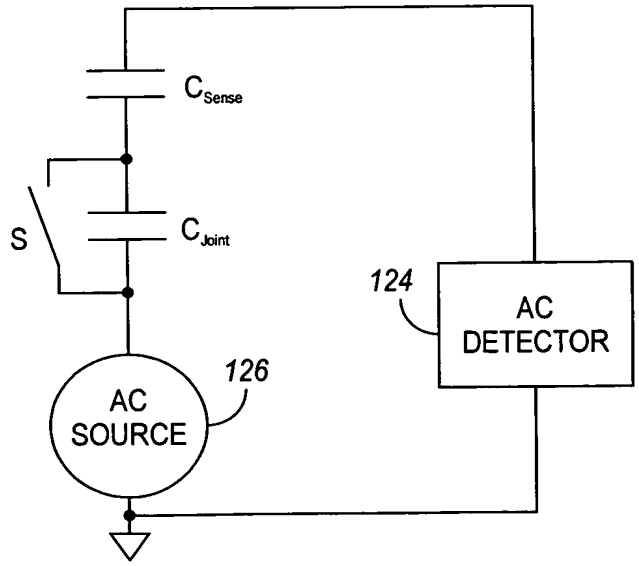
C_{Sense}
S
C_{Joint}
124
AC DETECTOR
126
AC SOURCE

FIG. 2

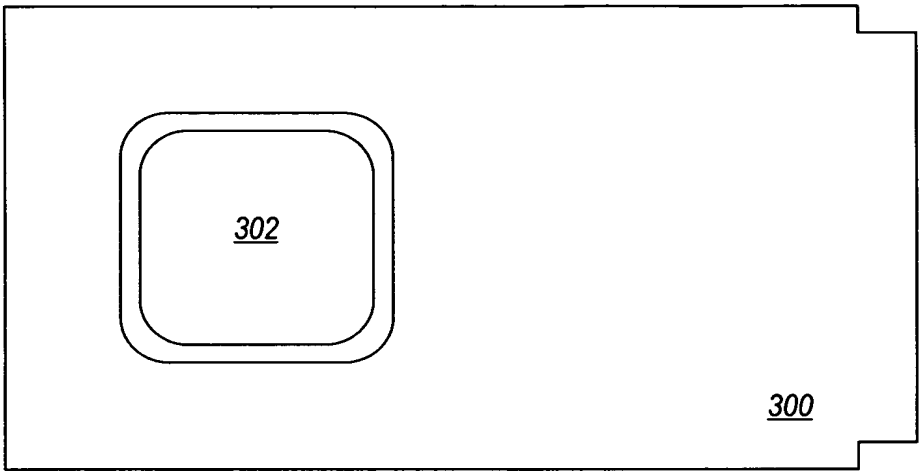

FIG. 3

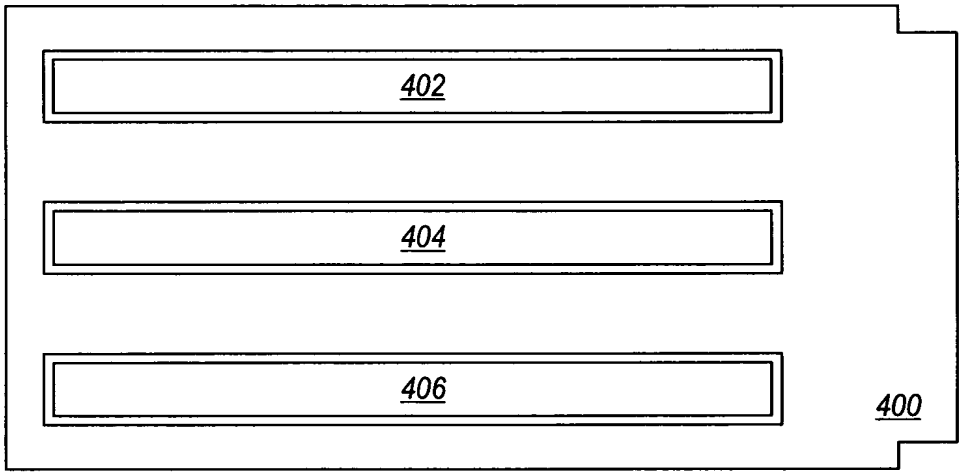

FIG. 4

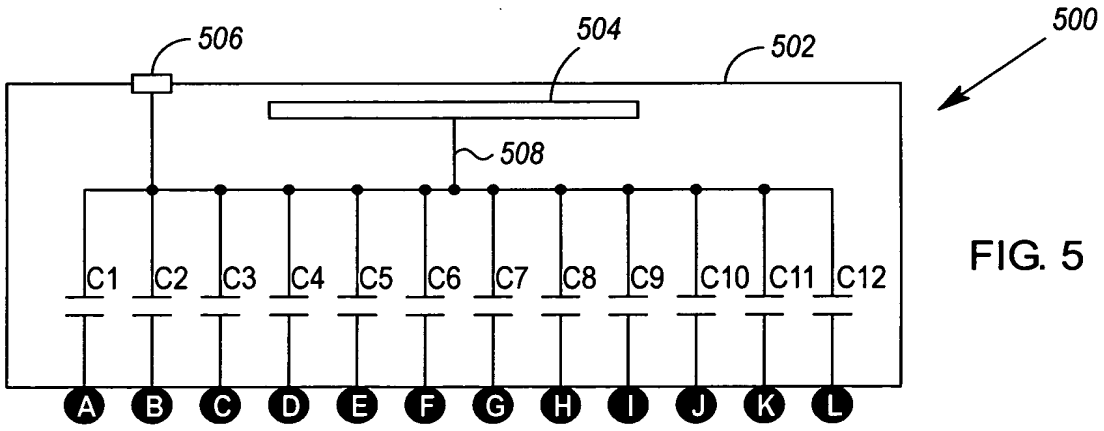

FIG. 5

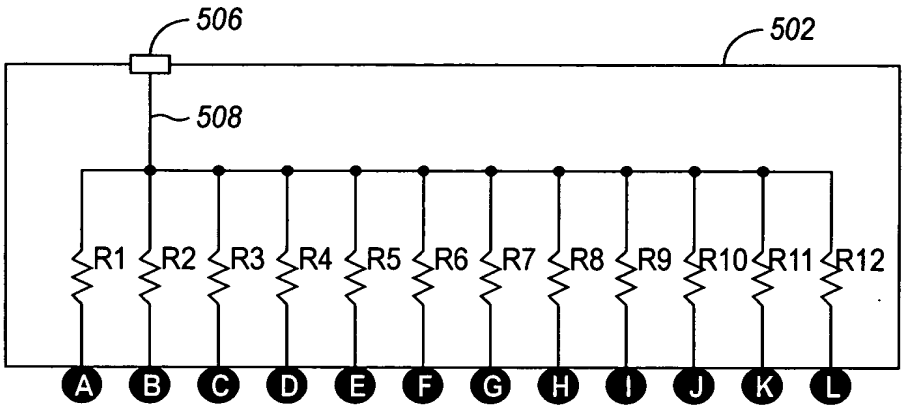
506
502
508
R1
R2
R3
R4
R5
R6
R7
R8
R9
R10
R11
R12
A
B
C
D
E
F
G
H
I
J
K
L

FIG. 6

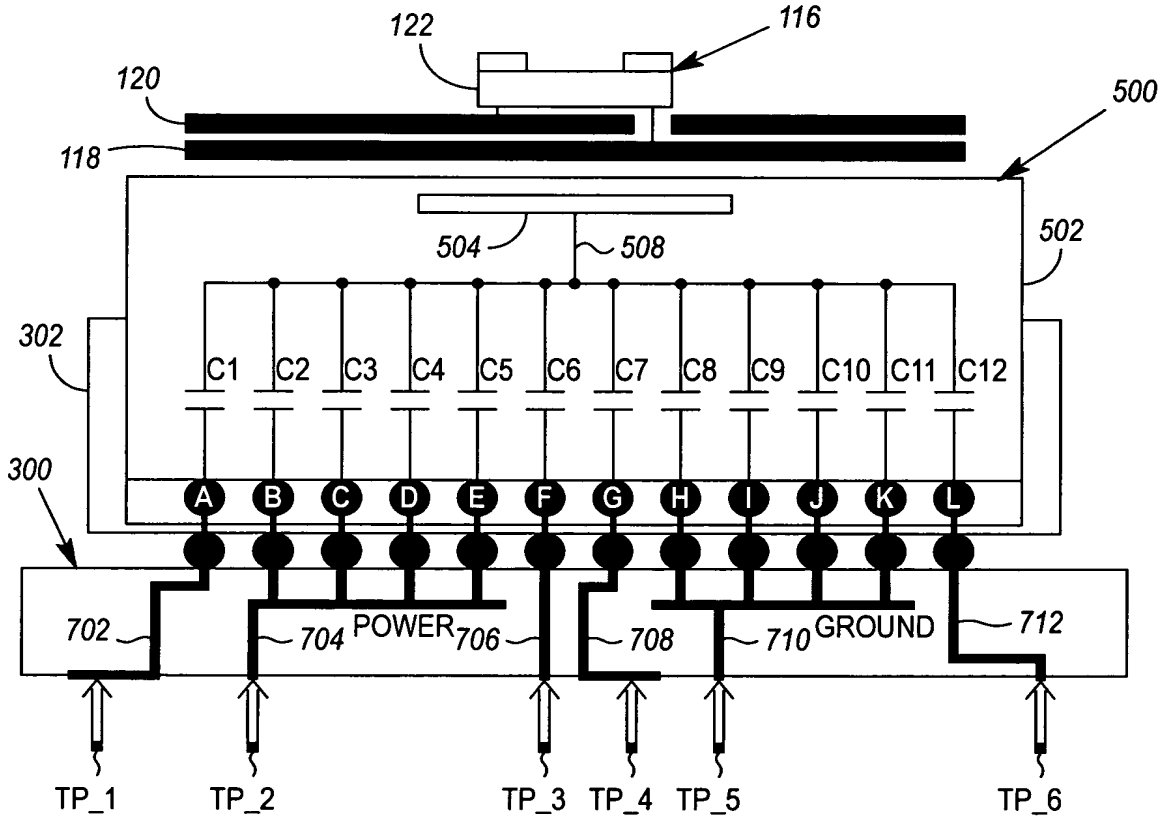
122
116
120
500
118
504
508
502
302
C1
C2
C3
C4
C5
C6
C7
C8
C9
C10
C11
C12
300
A
B
C
D
E
F
G
H
I
J
K
L
702
704
POWER
706
708
710
GROUND
712
TP_1
TP_2
TP_3
TP_4
TP_5
TP_6

FIG. 7

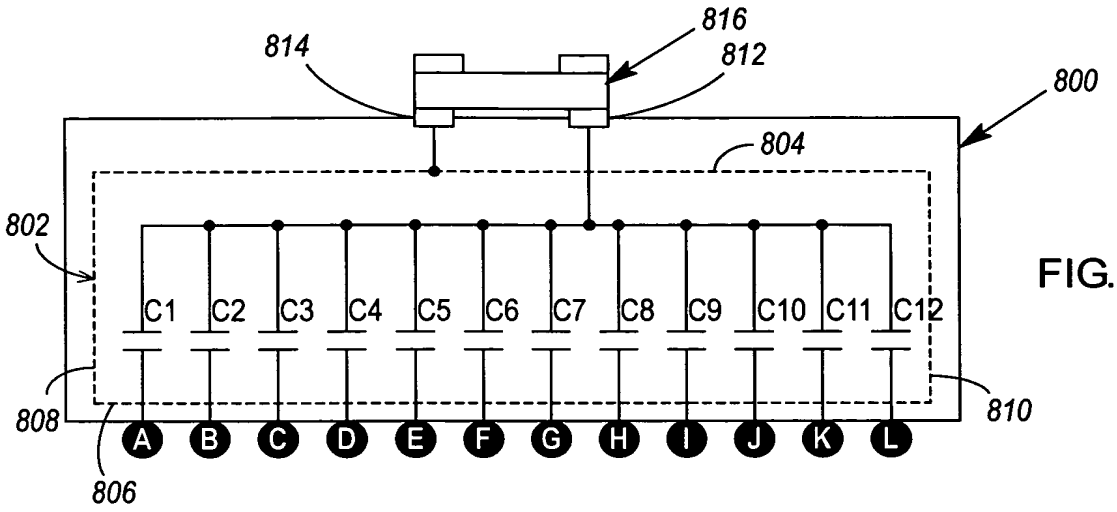

FIG. 8

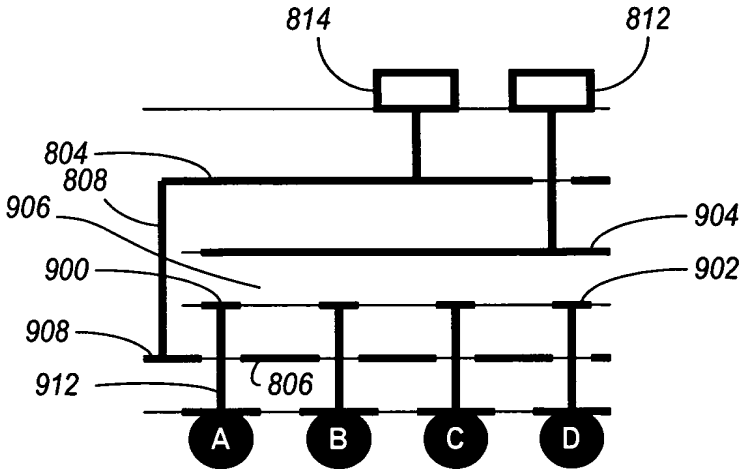

FIG. 9

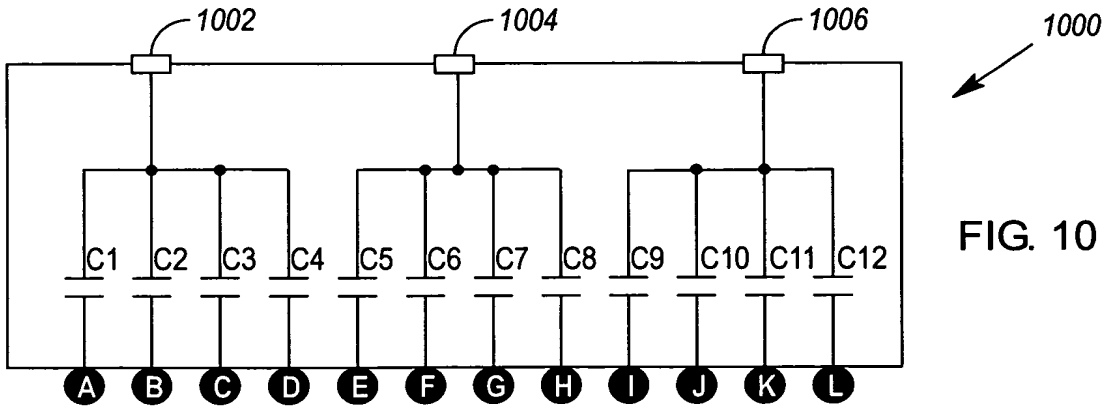

FIG. 10

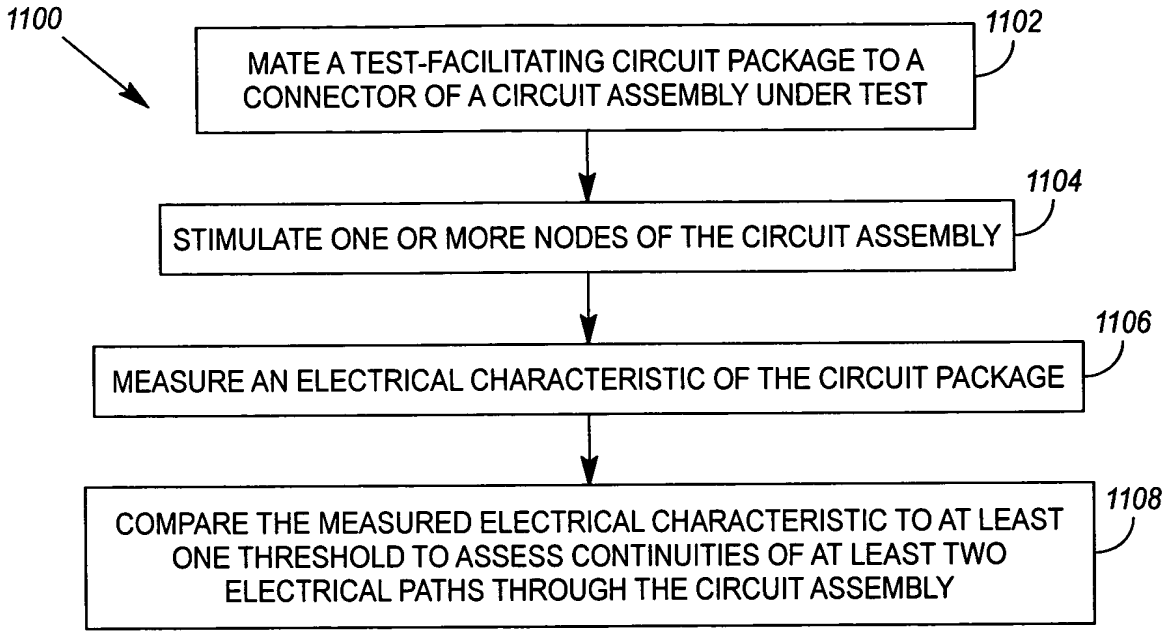
1100
MATE A TEST-FACILITATING CIRCUIT PACKAGE TO A CONNECTOR OF A CIRCUIT ASSEMBLY UNDER TEST
1102
STIMULATE ONE OR MORE NODES OF THE CIRCUIT ASSEMBLY
1104
MEASURE AN ELECTRICAL CHARACTERISTIC OF THE CIRCUIT PACKAGE
1106
COMPARE THE MEASURED ELECTRICAL CHARACTERISTIC TO AT LEAST ONE THRESHOLD TO ASSESS CONTINUITIES OF AT LEAST TWO ELECTRICAL PATHS THROUGH THE CIRCUIT ASSEMBLY
1108

FIG. 11

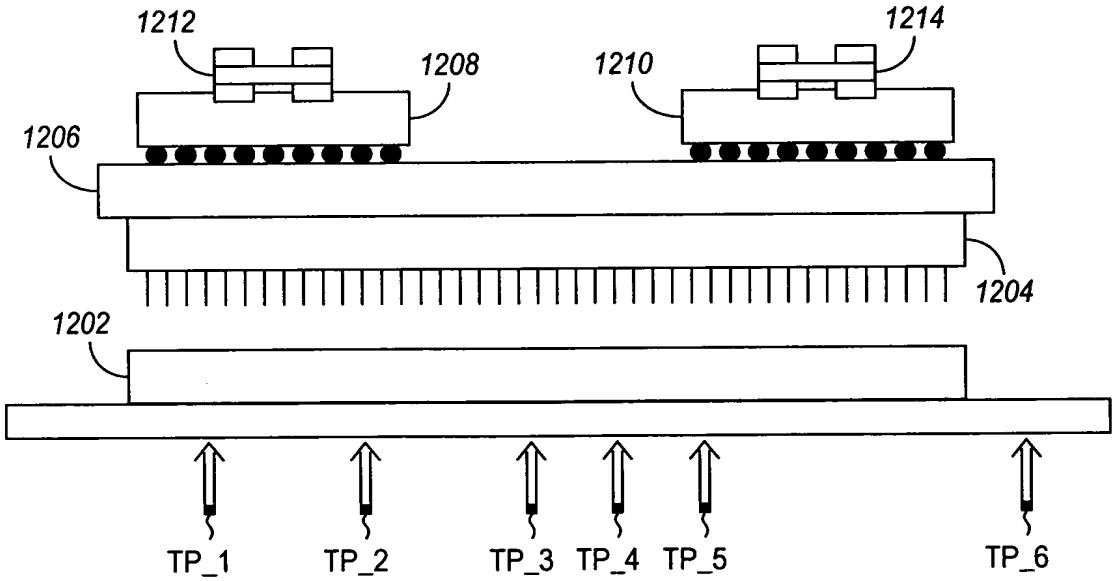
1212
1208
1214
1210
1206
1204
1202
TP_1
TP_2
TP_3
TP_4
TP_5
TP_6

FIG. 12

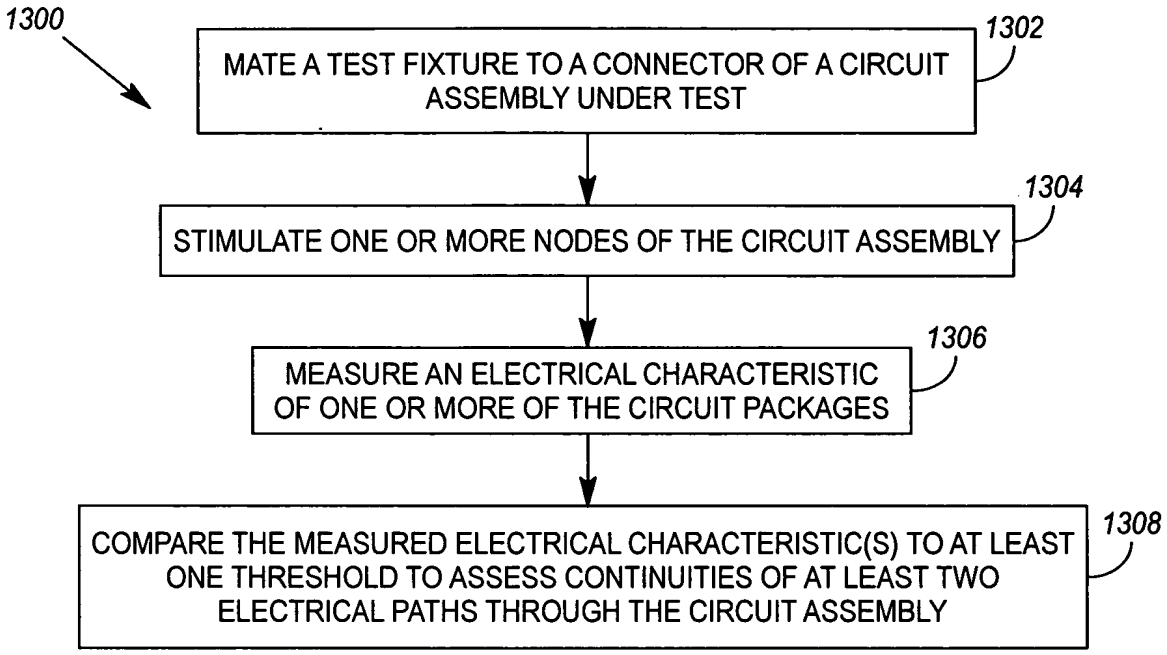
1300
MATE A TEST FIXTURE TO A CONNECTOR OF A CIRCUIT ASSEMBLY UNDER TEST
1302
STIMULATE ONE OR MORE NODES OF THE CIRCUIT ASSEMBLY
1304
MEASURE AN ELECTRICAL CHARACTERISTIC OF ONE OR MORE OF THE CIRCUIT PACKAGES
1306
COMPARE THE MEASURED ELECTRICAL CHARACTERISTIC(S) TO AT LEAST ONE THRESHOLD TO ASSESS CONTINUITIES OF AT LEAST TWO ELECTRICAL PATHS THROUGH THE CIRCUIT ASSEMBLY
1308

FIG. 13

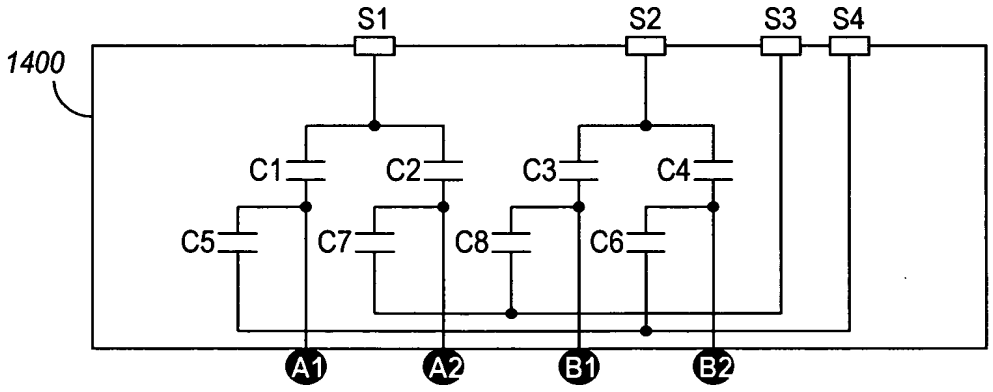
1400
S1
S2
S3
S4
C1
C2
C3
C4
C5
C7
C8
C6
A1
A2
B1
B2

FIG. 14